REMARKS

Request for Reconsideration

Applicants have carefully considered the matters raised by the Examiner in the outstanding Office Action but remain of the opinion that patentable subject matter is present. Applicants respectfully request reconsideration of the Examiner's position based on the above amendments to the claims and the following remarks.

Claims Status

Claims 1-21 had been pending in this Application and Claims 18-20 were withdrawn while Claims 1-17 and 21 were examined.

This Response amends Claim 12 to correct an obvious typographical error and cancels Claim 21. No additional amendments have been made, thus, Claims 1-17 are currently under examination.

Claim Objections

Claim 12 had been objected to for containing a typographical error. Claim 12 has been amended herein.

Claim rejections

Claims 1-4 and 9-17 had been rejected as being anticipated by Hattori, while Claims 5-8 had been objected to as being dependent upon rejected claims but indicated as allowable if rewritten in independent form.

With respect to the rejection based on Hattori, the Examiner recognized that Hattori fails to teach that the peeling layer contains a release layer which has a coating weight of more than 0 but not more than 3 g/m^2; that the transfer layer contains a photo cured resin layer having a coating weight of 3 to 15 g/m^2; that the peeling layer has a maximum electrostatic charge at peeling of 0 to 30 kV; and that the I.D. card has a maximum electrostatic charge of 0 to 10 kV at the peeling step. The Examiner took the position that it would be obvious for one of skill in the art to optimize these values to arrive at the present Invention. Applicants respectfully disagree.

First, it will be noted that Claims 1 and 2 are independent claims and that both of these claims share the limitation that the peeling layer has a releasing layer having a coating weight of more than 0 but not more than 3 g/m^2; and that the transfer layer has a photo cured resin

layer having a coating weight of 3 to 15 g/m^2. Claims 1 and 2 differ in that Claim 1 requires that the peeling layer have a maximum electrostatic charge of 0 to 30 kV at the peeling step, while Claim 2 requires that the I.D. card has a maximum electrostatic charge of 0 to 10 kV at the peeling step.

Applicants submit that it would not be obvious to obtain these values because superior results are obtained with these values. Specifically, Applicants direct the Examiner's attention to the data shown in the Tables as contained on pages 145 to 148 of the Application.

Specifically, the Examiner's attention is directed to Example 2 in Table 1-1 and is requested to compare this with Comparative Example 15 (see *19 15, *19 means "Comparative Example") in Table 1-4.

As can be seen by Tables 1-1 and 1-4, both Example 2 and Comparative Example 15 use the same I.D. card substrate, I.D. card substrate 1, and were both prepared using the same I.D. card preparation apparatus, the one shown in Figure 16.

It can be seen that Example 2 in Table 1-1 had a peeling layer with a maximum electrostatic charge of 28 during peeling and that the I.D. card had a maximum electrostatic charge of 6 kV during the peeling step. Thus, Example 2 in Table 1-1, falls within the limitations of both Claims 1 and 2. Claim 1 recites that the peeling layer has a maximum electrostatic charge of 0 to 30 kV during peeling while Claim 2 recites that the I.D. card has a maximum electrostatic charge of 0 to 10 kV during peeling.

In contrast, Comparative Example 15 does not fall within Claims 1 or 2 because Comparative Example 15, as reported in Table 1-4, has a peeling layer with a maximum electrostatic charge of 45 kV during peeling and the I.D. card has a maximum electrostatic charge of 18 during peeling. Both of these were outside the range of Claims 1 and 2, respectively.

Comparing the results between Example 2 in Table 1-1 and Example 15 in Table 1-4, it can be seen that Example 2 produced far superior results to Comparative Example 15. For example, the scratch resistance (*11) for Example 2 was 253 while the scratch resistance for Example 15 was 146.

The ratio of cards with adhere dust particles for Example 2 of Table 1-1 was 0% while the ratio of cards with adhered dust particles was 8.6% for Comparative Example 15 as reported in Table 1-4. The tests for chemical resistance (*15) shows that Example 2 rated an A which means no difference was noted from the initial card after the card was immersed in a 50% IPA solution at a temperature of 25° for one day. This is contrasted against Comparative Example 15 which rated a C which meant that the image information was lost.

Respectfully, one of skill in the art upon reading Hattori would not be led to preparing an I.D. card under specific conditions as recited in Claims 1 and 2 and, specifically, not led to producing an I.D. card wherein either a peel layer had a maximum electrostatic charge of 0 to 30 kV at the peeling step nor the I.D. card having a maximum electrostatic charge of 0 to 10 kV at the peeling step.

In view of the foregoing, it is respectfully submitted that Claims 1 and 2 is neither taught nor suggested by Hattori.

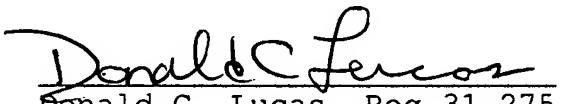
Conclusion

In view of the foregoing, it is respectfully submitted that the Application is in condition for allowance and such action is respectfully requested.

Should any extensions of time or fees be necessary in order to maintain this Application in pending condition, appropriate requests are hereby made and authorization is given to debit account # 02-2275.

Respectfully submitted,

LUCAS & MERCANTI, LLP

By: 

Donald C. Lucas, Reg.31,275
(Attorney for Applicant(s)
475 Park Avenue South
New York, New York 10016
Tel. # (212) 661-8000

DCL/mr

Encl: Return receipt post-card